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# Nanoscale Memory Repair

 Springer

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ISSN 1558-9412  
ISBN 978-1-4419-7957-5 e-ISBN 978-1-4419-7958-2  
DOI 10.1007/978-1-4419-7958-2  
Springer New York Dordrecht Heidelberg London

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Printed on acid-free paper

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## Preface

Repair techniques for nanoscale memories are becoming more important to cope with ever-increasing “errors” causing degraded yield and reliability. In fact, without repair techniques, even modern CMOS LSIs, such as MPUs/SoCs, in which memories have dominated the area and performances, could not have been successfully designed. Indeed, various kinds of errors have been prominent with larger capacity, smaller feature size, and lower voltage operations of such LSIs. The errors are categorized as hard/soft errors, timing/voltage margin errors, and speed-relevant errors. Hard/soft errors and timing/voltage margin errors, which occur in a chip, are prominent in a memory array because the array comprises memory cells having the smallest size and largest circuit count in the chip. In particular, coping with the margin errors is vital for low-voltage nanoscale LSIs, since the errors rapidly increase with device and voltage scaling. Increase in operating voltage is one of the best ways to tackle the issue. However, this approach is unacceptable due to intolerably increased power dissipation, calling for other solutions by means of devices and circuits. Speed-relevant errors, which are prominent at a lower voltage operation, comprise speed-degradation errors of the chip itself and intolerably wide chip-to-chip speed-variation errors caused by the ever-larger interdie design-parameter variation. They must also be solved with innovative devices and circuits. For the LSI industry, in order to flourish and proliferate, the problems must be solved based on in-depth investigation of the errors.

Despite the importance, there are few authoritative books on repair techniques because the solutions to the problems lie across different fields, e.g., mathematics and engineering, logic and memories, and circuits and devices. This book systematically describes the issues, based on the authors’ long careers in developing memories and low-voltage CMOS circuits. This book is intended for both students and engineers who are interested in the yield, reliability, and low-voltage operation of nanoscale memories. Moreover, it is instructive not only to memory designers, but also to all digital and mixed-signal LSI designers who are at the leading edge of such LSI developments.

Chapter 1 describes the basics of repair techniques. First, after categorizing sources of hard/soft errors, the reductions by means of redundancy, error checking

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